


<b>Search Notes</b>  	<b>Application/Control No.</b>  10525696	<b>Applicant(s)/Patent Under Reexamination</b>  CRUZ ET AL.
	<b>Examiner</b>  ALLAHYAR KASRAIAN	<b>Art Unit</b>  2617

### SEARCHED

Class	Subclass	Date	Examiner
370	318	9/15/2008	AK

### SEARCH NOTES

Search Notes	Date	Examiner
EAST Image and keyword search in USPTO, US-PGPUB, DERWENT, EPO, JPO, and IBM TDB (see attached search strategy)	9/22/2008	AK
Inventor name and Assignee search in PALM ExPo and EAST	9/8/2008	AK
(370/318,317,395.4.ccls. 455/522,67.11,13.4,453,500,501,513,127.1.ccls.) and ((measur\$3 with (SNR SIR SINR "signal to noise" "signal to interference")) same (data adj2 rate)) and (@ad<="20020905" @rlad<="20020905")	9/8/2008	AK
IEEE Xplore: <a href="http://ieeexplore.ieee.org/Xplore/DynWel.jsp">http://ieeexplore.ieee.org/Xplore/DynWel.jsp</a>	9/8/2008	AK
Google: <a href="http://www.google.com">http://www.google.com</a>	9/8/2008	AK
EPO Data base: <a href="http://ep.espacenet.com">http://ep.espacenet.com</a>	9/8/2008	AK
Constulted with Rafael Pérez-Gutiérrez	9/8/2008	AK
updated search	4/3/2009	AK

### INTERFERENCE SEARCH

Class	Subclass	Date	Examiner

/A. K./  
Examiner, Art Unit 2617